Concurrent Test Supported by DFT Techniques and ATE Companies

Abstract:
Concurrent Test needs support by DFT and ATE. A lot of devices are suitable for concurrent test, but what about ATE hardware and software? Do they support concurrent test adequately? What are the different philosophies in DFT and ATE hardware and software?

Description:
Within that panel the silicon vendors present their thoughts about some DFT techniques supporting Concurrent Test followed by their requirement towards ATE. The four ATE representatives present their visions of how to realize concurrent test on their equipment.

The following important questions should be discussed during the panel:
- What is concurrent test?
- What are the requirements by DFT?
- How to enable concurrent test?
- How to minimize the manpower effort on ATE side to come there?
- Costs & return of investment?
- Is concurrent test more a ATE hardware or software issue?
- When is concurrent test an available standard method?

Organizer:
Ralf Arnold, Infineon Technologies, Germany

Moderator:
John Carulli, Texas Instruments, US

Panelists:
John Shelley, LTXC, US
Mani Balaraman, Advantest, US
Erik Volkerink, Verigy, US
Randy Kramer, Teradyne, US
Ralf Arnold, Infineon Technologies, Germany